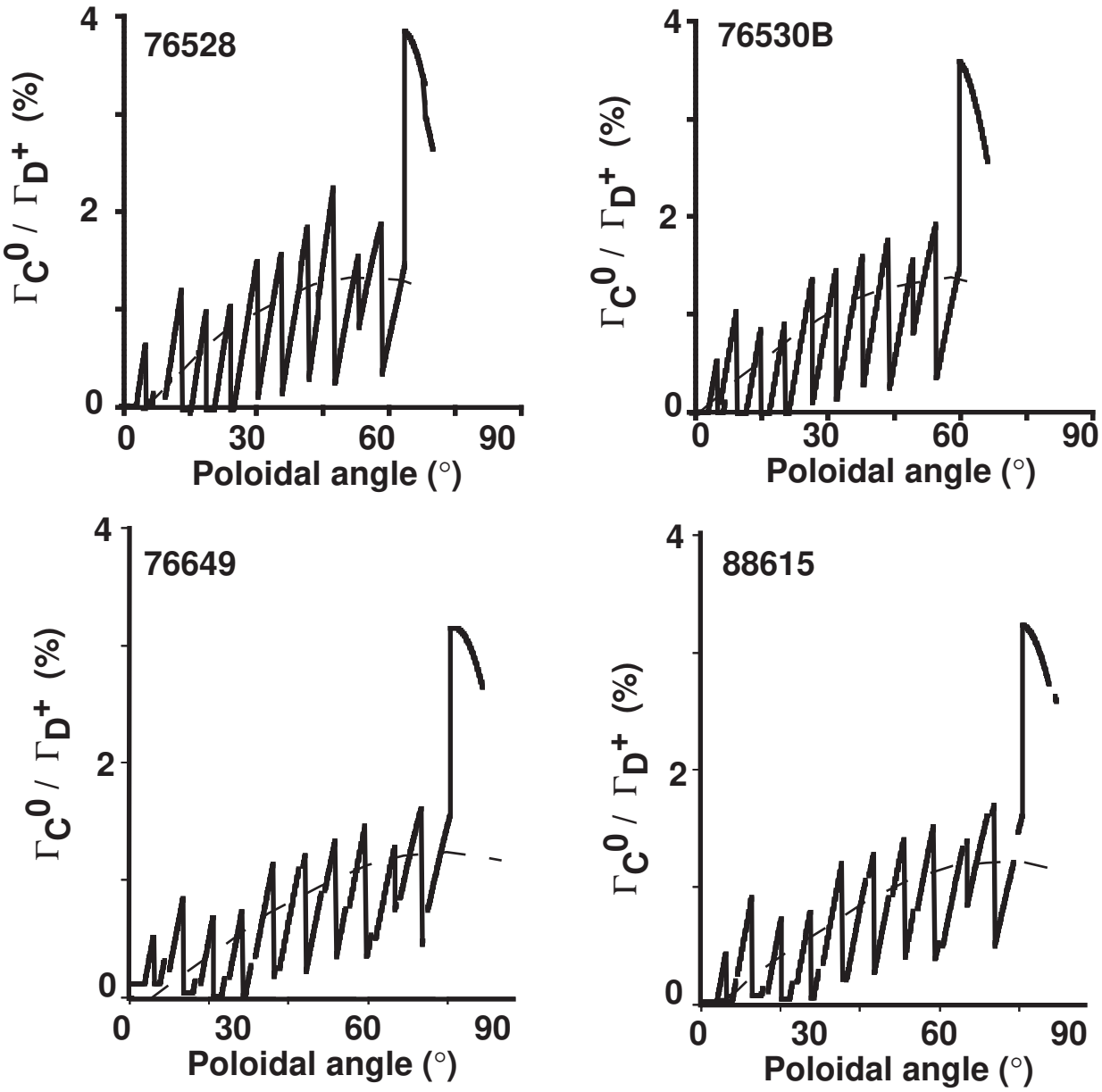

FIG. 3

Calculated local effective sputtering yield distributions (emitted impurity flux / incident D^+ flux) for the four cases of Table 2, with $\Gamma_\perp (0) / \Gamma_{//}(0) = 0.001$